



FDP6670AS/FDB6670AS

30V N-Channel PowerTrench® SyncFET[™]

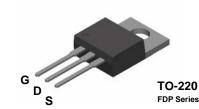
General Description

This MOSFET is designed to replace a single MOSFET and parallel Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\rm DS(ON)}$ and low gate charge. The FDP6670AS includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDP6670AS/FDB6670AS as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDP6670A/FDB6670A in parallel with a Schottky diode.

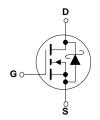
Features

• 31 A, 30 V. $R_{DS(ON)} = 8.5 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 10.5 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$

- Includes SyncFET Schottky body diode
- Low gate charge (28nC typical)
- High performance trench technology for extremely low R_{DS(ON)} and fast switching
- · High power and current handling capability







S TO-263AB FDB Series

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous		62	Α
	Pulsed	(Note 1)	150	
P _D	Total Power Dissipation @ T _C = 25°C		62.5	W
	Derate ab	ove 25°C	0.5	W/°C
T_J , T_{STG}	Operating and Storage Junction Temperatu	re Range	–55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		275	°C

Thermal Characteristics

R _{θJC}	Thermal Resistance, Junction-to-Case	2.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking		Device	Reel Size	Tape width	Quantity
	FDB6670AS	FDB6670AS	13"	24mm	800 units
	FDP6670AS	FDP6670AS	Tube	n/a	45

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		1			
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 1\text{mA}$	30			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 10mA, Referenced to 25°C		27		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			500	μΑ
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1mA$	1	1.7	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I _D = 10mA, Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 31 \text{ A}$		6.8	8.5	mΩ
	On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 26.5 \text{ A}$		8.4 9	10.5 12.5	
	On State Drain Summer	V _{GS} =10 V, I _D =31 A, T _J =125°C	60	9	12.3	Δ.
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$	60	0.4		A
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 31 \text{ A}$		84		S
	Characteristics	1		ı	1	1
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		1570		pF
Coss	Output Capacitance	f = 1.0 MHz		440		pF
C _{rss}	Reverse Transfer Capacitance			160		pF
R _G	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		1.9		Ω
Switchir	g Characteristics (Note 2)			-		
$t_{\text{d(on)}}$	Turn-On Delay Time			9	18	ns
t _r	Turn-On Rise Time	$V_{DS} = 15 \text{ V}, I_{D} = 1 \text{ A},$		12	22	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		27	43	ns
t_f	Turn-Off Fall Time			19	34	ns
t _{d(on)}	Turn-On Delay Time			16	29	ns
t_r	Turn-On Rise Time	$V_{DS} = 15 \text{ V}, I_{D} = 1 \text{ A},$		16	29	ns
$t_{\text{d(off)}} \\$	Turn-Off Delay Time	V_{GS} = 4.5 V, R_{GEN} = 6 Ω		25	40	ns
t_f	Turn-Off Fall Time			13	23	ns
Q_{g}	Total Gate Charge, Vgs=10V			28	39	nC
Q_gs	Gate-Source Charge, Vgs=5V	$V_{DS} = 15 \text{ V}, I_{D} = 31 \text{ A},$		15	21	nC
Q_{gd}	Gate-Drain Charge			5		nC
\mathbf{Q}_{gd}	Gate-Drain Charge			5		nC
Drain-S	ource Diode Characteristics					
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 3.5 \text{ A}$ (Note 1) $V_{GS} = 0 \text{ V}, I_S = 7 \text{ A}$ (Note 1)		0.5 0.6	0.7 0.9	V
t _{rr}	Diode Reverse Recovery Time	I _F = 3.5 A,		20		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 2)		14		nC

Notes:

^{1.} Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

^{2.} See "SyncFET Schottky body diode characteristics" below.

Typical Characteristics

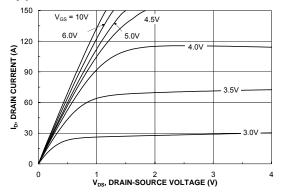


Figure 1. On-Region Characteristics.

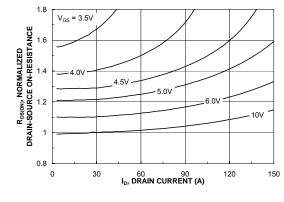


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

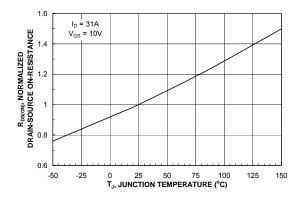


Figure 3. On-Resistance Variation with Temperature.

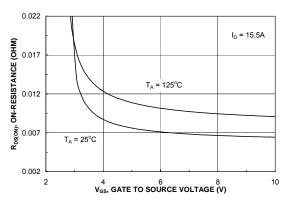


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

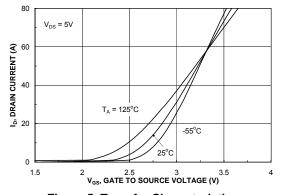


Figure 5. Transfer Characteristics.

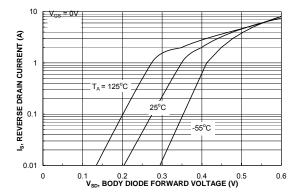
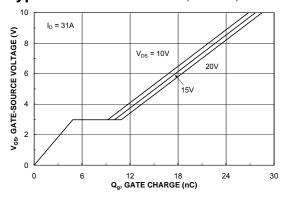


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



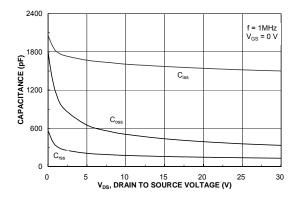
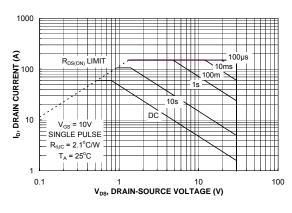


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



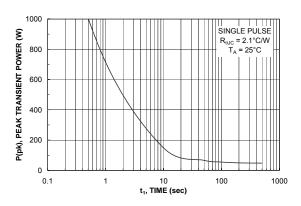


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

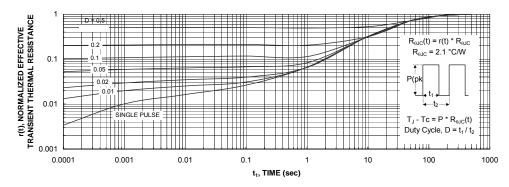


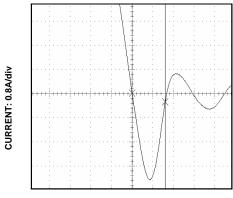
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 FDP6670AS.



TIME: 12.5ns/div

Figure 12. FDP6670AS SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDP6670A).

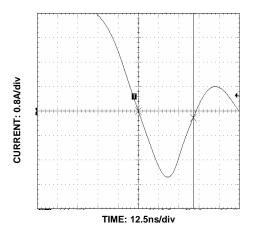


Figure 13. Non-SyncFET (FDP6670A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

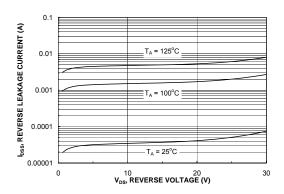
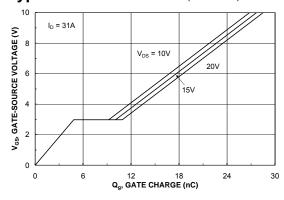


Figure 14. SyncFET diode reverse leakage versus drain-source voltage and temperature.

Typical Characteristics (continued)



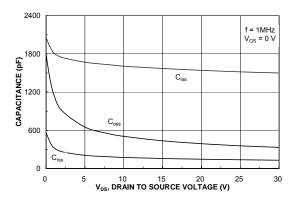
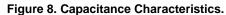
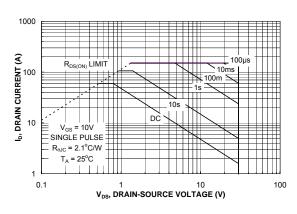


Figure 7. Gate Charge Characteristics.





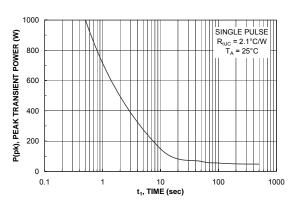


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

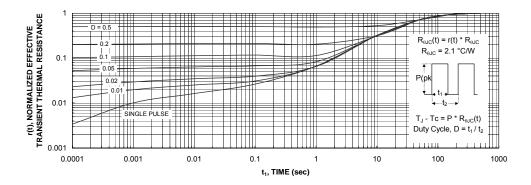


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.





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